IEEE 19th Asian Test Symposium
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SHERATON Hotel, http://ats10.shu.edu.cn

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CALL FOR PAPERS

ATS 2010 is the nineteenth in this series of symposia started in 1992 that are devoted to testing and fault tolerant computing. ATS is now recognized as the main regular event of the word that is covering the many dimensions of Testing for computing systems. The symposium will be organized by the Shanghai University, Shanghai, the most modernized city of China. Shanghai is a vibrant blend of traditional culture and cosmopolitan life and it is the economic, educational and recreational center of the country, offering a variety of significant cultural sights. The famous 2010 World Expo will be held in Shanghai where a number of brilliant buildings and exhibition halls in different styles will be shown to the world.

Objective:

Following the traditions set up by its predecessors, this year ATS 2010 aims at providing a more open forum for worldwide researchers and industrial practitioners to exchange their innovative ideas on testing technology for both hardware and software in computing systems. ATS 2010 will stress its theme on the "New development and applications of testing technology", covering all aspects of technical issues on design-for-testability, test integration, diagnosis, repair, and yield enhancement of a complex chip with embedded digital, analog, and/or memory components.

Scope:

Original contributions on VLSI testing are solicited. Topics of interest include, but are not limited to, the following categories:

1. Test generation & fault simulation	2. DfX: Design for testability, reliability, dependability…
3. Fault diagnosis	4. Analog & mixed-signal testing / RF/ High speed I/O testing
5. Memory testing and FPGA testing	6. Wafer-level testing
7. Delay fault testing / Low power testing	8. Board and system testing / On-line testing
9. System-on-a-chip- test/ System-in-package test	10. Network-on-a-chip testing
11. Software testing / verification	12. CPU testing
13. Failure analysis / fault modeling	14. Built-in self-test / Embedded testing
15. Fault tolerance / error correction	16. Functional testing
17. IDDQ testing	18. Test economics
19. Test standard: IEEE 1500, boundary scan	20. Test experience in industry
21. Automatic test equipment	22. Yield Enhancement / Silicon debug

Paper Submissions:

Manuscripts should be submitted in the following categories: Regular Papers and Practical Experience Reports. Regular Papers should describe original research (not submitted or published elsewhere) and be not more than 20 double-spaced pages including figures and tables using 11- point type. Practical Experience Reports (of 5-12 pages) should describe an experience or a case study, such as the design and deployment of a system or actual failure and recovery field data. The title page should include a 150-word abstract, five keywords, authors' names and affiliations and a line specifying whether the submission is a Regular Paper or a Practical Experience Report. The full mailing address, phone, fax and email address of the corresponding author should be specified. All submissions must be made electronically (in PDF format) on web site (http://ats10.shu.edu.cn). Please visit our web site for full submission instructions and updated information on the symposium.

Papers will be reviewed internationally and selected based on their originality, significance, relevance, and clarity of presentation. All accepted papers will be published in ATS Proceedings by IEEE Computer Society Conference Publication Service (CPS) and will be EI and ISTP indexed.

Important Dates Due
Submission: May 24th 2010; Notification: July 14th 2010; Final Version: August 18th 2010
Tutorial: December 1st, 2010 ; Symposium: December 2nd, 2010

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